Title (en)

USER INTERFACE FOR QUANTIFYING WAFER NON-UNIFORMITIES AND GRAPHICALLY EXPLORE SIGNIFICANCE

Title (de)

BENUTZEROBERFLÄCHE ZUR QUANTIFIZIERUNG VON SCHEIBENUNREGELMÄSSIGKEITEN UND GRAPHISCHE UNTERSUCHUNGSSIGNIFIKANZ

Title (fr)

INTERFACE UTILISATEUR PERMETTANT DE QUANTIFIER LES ASPECTS NON UNIFORMES D'UNE PLAQUETTE ET D'EXPLORER GRAPHIQUEMENT LEUR SIGNIFICATION

Publication

EP 1543550 A2 20050622 (EN)

Application

EP 03756878 A 20030924

Priority

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- US 41402102 P 20020926
- US 33119402 A 20021224
- US 45224803 A 20030530

Abstract (en)

[origin: WO2004030083A2] A wafer viewer system is provided for graphical presentation and analysis of a wafer and a wafer series. More specifically, the wafer viewer system includes a graphical user interface for displaying a wafer, graphically selecting regions of the wafer for analysis, performing analysis on the selected regions of the wafer, and displaying results of the analysis.

IPC 1-7

H01L 21/66

IPC 8 full level

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